

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/833,528	JIANG ET AL.	
Examiner		Art Unit		Page 1 of 2
Feben M Haile		2663		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,667,991	12-2003	Tzannes, Marcos	370/465
	B	US-2003/0074674	04-2003	Magliaro, Maximilian Matthew	725/118
	C	US-6,292,875	09-2001	Tanaka et al.	711/154
	D	US-6,014,693	01-2000	Ito et al.	709/219
	E	US-6,178,213	01-2001	McCormack et al.	375/355
	F	US-6,075,787	06-2000	Bobeck et al.	370/395.2
	G	US-2004/0091028	05-2004	Aronson et al.	375/219
	H	US-2003/0043432	03-2003	Marmor et al.	359/152
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004023732 A	01-2004	Japan	WATANABE, TAKAHIRO	H04L 29/06
	O	EP 702474 A1	03-1996	European Patent	DUAULT et al.	H04L 12/56
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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